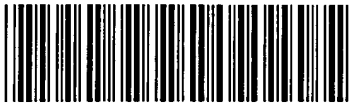


**Search Notes**

Application/Control No.

10/770,295

Examiner

Jacob F. Betit

Applicant(s)/Patent under  
Reexamination

CHANG ET AL.

Art Unit

2164

**SEARCHED**

Class	Subclass	Date	Examiner
707	1-10	7/7/2006	EE
715	501.1	7/7/2006	EE

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST Search	7/7/2006	EE
Consulted Pham Khanh (primary)	7/7/2006	EE
searched EAST	12/22/2006	JFB